Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,160	CHIU, WEN-PIN
Examiner	Art Unit
Rodney G. McDonald	1753

	SEARCHED						
Class	Subclass	Date	Examiner				
204	142.12	2/15/07	The				
1	192-17	2/15/07					
	192.15						
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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